

Notice of References Cited	Application/Control No. 10/761,972	Applicant(s)/Patent Under Reexamination DOVE ET AL.	
	Examiner Benny Lee	Art Unit 2817	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,426,399	06-1995	Matsubayashi et al.	333/1
	B	US-5,317,292	05-1994	Leeb, Karl-Erik	333/238
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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